

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/911,873	IKEDA ET AL.	
Examiner	Art Unit	

Benny Q. Tieu

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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
		DATE	EXMR		
EAST		5/26/2005	BQT		
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